INFORMATION			Customer Number	ATTORNEY'S DKT NO. H1107		APPLICATION No. Unassigned			
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).

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ATTORNEY'S DKT NO. H1107

APPLICATION No. 10/699,887

APPLICANT(S)

Cyrus E. Tabery et al.

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